

L Number	Hits	Search Text	DB	Time stamp
1	8	"5744381"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:25
2	318	(image near3 pickup) and (storing or store) and control\$4 and display\$4 and defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:27
3	29	((image near3 pickup) and (storing or store) and control\$4 and display\$4 and defect) and (locat\$4 near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:27
4	0	((image near3 pickup) and (storing or store) and control\$4 and display\$4 and defect) and (locat\$4 near4 defect)) and (scale near (factor or value))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:28
5	4	((image near3 pickup) and (storing or store) and control\$4 and display\$4 and defect) and (locat\$4 near4 defect)) and (scale scale)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:49
7	7	((first adj scale) and (second adj scale) and defect) and (locat\$5 near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:55
8	9	((first adj scale) and (second adj scale) and defect) and ((locat\$5 or detect\$5) near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 11:55
6	35	(first adj scale) and (second adj scale) and defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:06
9	2120	(imag\$4 near4 (sample or wafer or substrate)) and ((locat\$5 or detect\$4) near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:07
10	153	((imag\$4 near4 (sample or wafer or substrate)) and ((locat\$5 or detect\$4) near4 defect)) and (scal\$4 near2 (up or coefficient or value or factor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:10
11	2	((imag\$4 near4 (sample or wafer or substrate)) and ((locat\$5 or detect\$4) near4 defect)) and (scal\$4 near2 (up or coefficient or value or factor))) and (second near scal\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:14
12	186	second adj scale adj factor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:15
13	119	(second adj scale adj factor) and (first adj scale adj factor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:15

14	1	((second adj scale adj factor) and (first adj scale adj factor)) and defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/14 12:16
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